

STL52N25M5

N-channel 250 V, 0.064 Ω 28 A, PowerFLAT™ (5x6) MDmesh™ V Power MOSFET

Features

Туре	V _{DSS}	R _{DS(on)} max.	I _D ⁽¹⁾
STL52N25M5	250 V	< 0.076 Ω	28 A

- 1. This value is rated according $R_{thj-case}$.
- Amongst the best R_{DS(on)}* area
- Very low profile package (1 mm max.)
- Excellent switching performance
- High dv/dt capability
- 100% avalanche tested

Application

Switching applications

Description

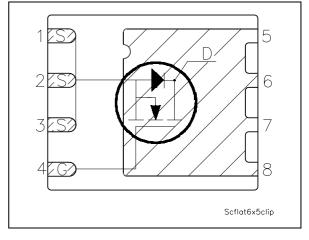
This device is N-channel MDmesh[™] V Power MOSFET based on an innovative proprietary vertical process technology, which is combined with STMicroelectronics' well-known PowerMESH[™] horizontal layout structure. The resulting product has extremely low onresistance, which is unmatched among siliconbased Power MOSFETs, making it especially suitable for applications which require superior power density and outstanding efficiency.

Table	1.	Device	summary
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PowerFLAT™ (5x6)
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Figure 1.

e 1. Internal schematic diagram



Order code	Marking	Package	Packaging
STL52N25M5	52N25M5	PowerFLAT™ (5x6)	Tape and reel

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Electrical ratings 1

Table 2. Absolute maximum ratings

Symbol	Parameter	Value	Unit
V _{GS}	Gate- source voltage	25	V
I _D ⁽¹⁾	Drain current (continuous) at $T_C = 25 \ ^{\circ}C$	28	А
I _D ⁽¹⁾	Drain current (continuous) at T _C = 100 °C	18	А
I _{DM} ^{(1),(2)}	Drain current (pulsed)	112	А
I _D ⁽³⁾	Drain current (continuous) at $T_C = 25 \ ^{\circ}C$	4.2	А
I _D ⁽³⁾	Drain current (continuous) at T _C = 100 °C	2.6	А
I _{DM} ^{(2),(3)}	Drain current (pulsed)	16.8	А
P _{TOT} ⁽¹⁾	Total dissipation at $T_C = 25 \ ^{\circ}C$	110	W
P _{TOT} ⁽³⁾	Total dissipation at $T_C = 25 \ ^{\circ}C$	2.5	W
I _{AR}	Avalanche current, repetitive or not-repetitive (pulse width limited by T_J max)	10	А
E _{AS}	Single pulse avalanche energy (starting $T_J = 25 \text{ °C}, I_D = I_{AR}, V_{DD} = 50 \text{ V}$)	230	mJ
dv/dt ⁽⁴⁾	Peak diode recovery voltage slope	15	V/ns
T _J T _{stg}	Operating junction temperature Storage temperature	- 55 to 150	°C

1. This value is rated according $R_{thj-case}$.

2. Pulse width limited by safe operating area.

3. This value is rated according $R_{thj-a.}$

4. $I_{SD} \leq$ 28 A, di/dt \leq 400 A/µs, V_{DD} = 150 V, $V_{Peak} < V_{(BR)DSS}$.

Thermal data

4. $I_{SD} \leq 28$ A, $dl/dt \leq 400$ A/ μ s, $V_{DD} = 150$ V, $V_{Peak} < V_{(BR)DSS}$.					
26	Table 3.	Thermal data			
-vSU.	Symbol	Parameter	Value	Unit	
$O_{\mathcal{P}}$	R _{thj-case}	Thermal resistance junction-case max	1.14	°C/W	
	R _{thj-a} ⁽¹⁾	Thermal resistance junction-amb max	50	°C/W	
	TJ	Maximum lead temperature for soldering purpose	300	°C/W	

1. When mounted on FR-4 board of 1inch², 2oz Cu



2 **Electrical characteristics**

(T_C = 25 °C unless otherwise specified).

Symbol	Parameter	Test conditions	Min.	Тур.	Max.	Unit
V _{(BR)DSS}	Drain-source breakdown voltage	$I_{D} = 1 \text{ mA}, V_{GS} = 0$	250			V
I _{DSS}	Zero gate voltage drain current (V _{GS} = 0)	$V_{DS} = Max rating$ $V_{DS} = Max rating, T_{C}=125 °C$			1 100	μΑ μΑ
I _{GSS}	Gate-body leakage current (V _{DS} = 0)	V _{GS} = ± 25 V		(100	nA
V _{GS(th)}	Gate threshold voltage	$V_{DS} = V_{GS}$, $I_D = 100 \ \mu A$	3	4	5	V
R _{DS(on)}	Static drain-source on- resistance	V _{GS} = 10 V, I _D = 13 A	070	0.064	0.076	Ω
Table 5.	Dynamic	olete				
Symbol	Parameter	Test conditions	Min	Typ	Max	Unit

Table 4. On /off states

Table 5. Dynamic

	Symbol	Parameter	Test conditions	Min.	Тур.	Max.	Unit
	C _{iss} C _{oss} C _{rss}	Input capacitance Output capacitance Reverse transfer capacitance	V _{DS} = 50 V, f = 1 MHz, V _{GS} = 0	-	1770 110 17	-	pF pF pF
	C _{o(er)} ⁽¹⁾	Equivalent output capacitance energy related	V _{GS} = 0, V _{DS} = 0 to 80% V _{(BR)DSS}	-	93	-	pF
10	C _{o(tr)} ⁽²⁾	Equivalent output capacitance time related	V_{GS} = 0, V_{DS} = 0 to 80% $V_{(BR)DSS}$	-	178	-	pF
c01	Rg	Gate input resistance	f=1 MHz open drain	-	2.5	-	Ω
02	Qg	Total gate charge	V _{DD} = 200 V, I _D = 28 A,		47		nC
)~	Q _{gs}	Gate-source charge	V _{GS} = 10 V	-	10	-	nC
	Q_{gd}	Gate-drain charge	(see Figure 14)		24		nC

 $C_{o(er)}$ is a constant capacitance value that gives the same stored energy as C_{oss} while V_{DS} is rising from 0 to 80% V_{DSS} . 1.

2. $C_{o(tr)}$ is a constant capacitance value that gives the same charging time as C_{oss} while V_{DS} is rising from 0 to 80% V_{DSS} .



	.					
Symbol	Parameter	Test conditions	Min.	Тур.	Max	Unit
t _{d(V)}	Voltage delay time	V _{DD} = 125 V, I _D = 14 A,		40		ns
t _{r(V)}	Voltage rise time	$R_{G} = 4.7 \Omega$, $V_{GS} = 10 V$		18		ns
t _{f(i)}	Current fall time	(see Figure 13)	-	64	-	ns
	Crossing time	(see Figure 18)		82		ns

Table 6.Switching times

Table 7.Source drain diode

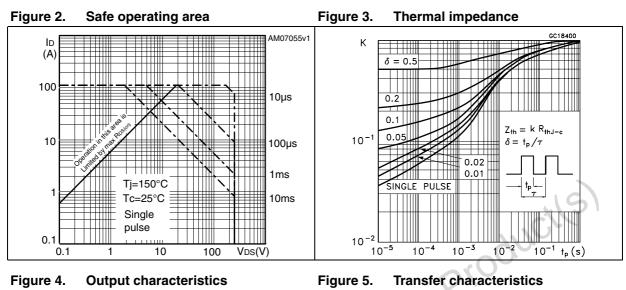
Symbol	Parameter	Test conditions	Min.	Тур.	Max	Unit
I _{SD} I _{SDM} ⁽¹⁾	Source-drain current Source-drain current (pulsed)		-	Ċ	28 112	A A
V _{SD} ⁽²⁾	Forward on voltage	I _{SD} = 28 A, V _{GS} = 0	_0	0	1.6	V
t _{rr}	Reverse recovery time	I _{SD} = 28 A, di/dt = 100 A/μs	5	168		ns
Q _{rr}	Reverse recovery charge	V _{DD} = 60 V, T _J = 25 °C	-	1.2		μC
I _{RRM}	Reverse recovery current	(see Figure 15)		14.5		А
t _{rr}	Reverse recovery time	I _{SD} = 28 A, di/dt = 100 A/μs		196		ns
Q _{rr}	Reverse recovery charge	V _{DD} = 60 V T _J = 150 °C	-	1.7		μC
I _{RRM}	Reverse recovery current	(see Figure 15)		17		А

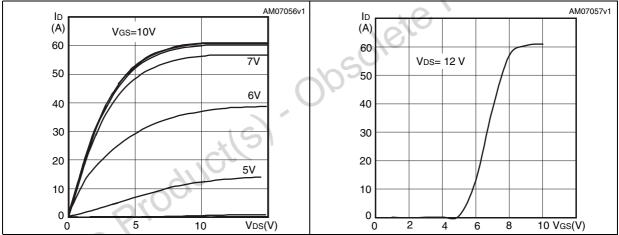
1. Pulse width limited by safe operating area.

2. Pulsed: pulse duration = 300 µs, duty cycle 1.5%.

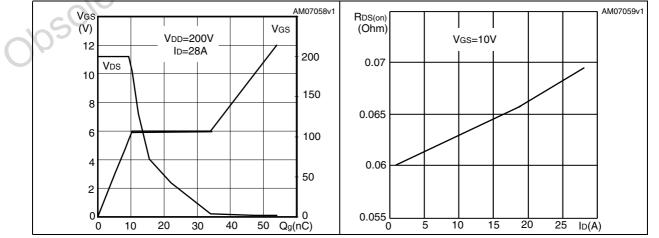


2.1 Electrical characteristics (curves)











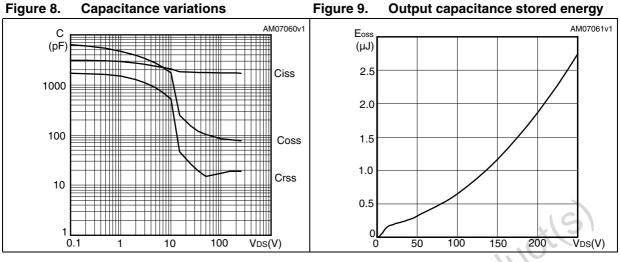


Figure 10. Normalized gate threshold voltage Figure 11. Normalized on resistance vs vs temperature

temperature

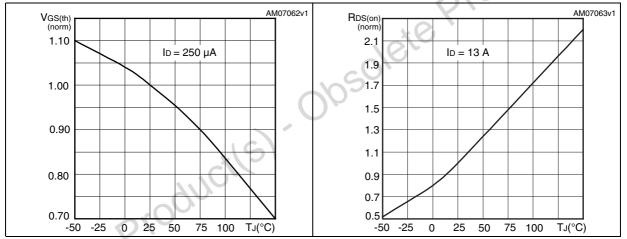
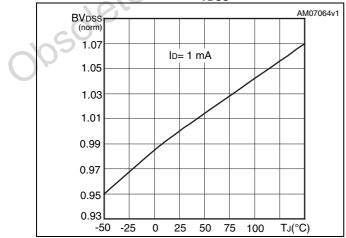


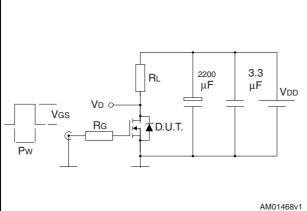
Figure 12. Normalized B_{VDSS} vs temperature





Test circuits 3

Figure 13. Switching times test circuit for resistive load



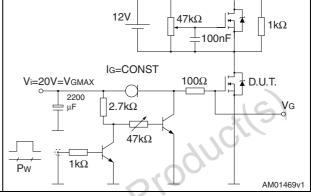
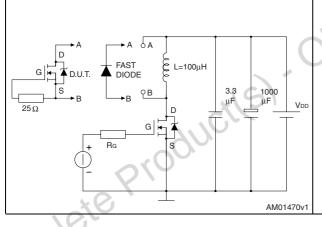
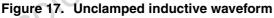
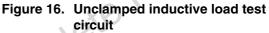


Figure 14. Gate charge test circuit

Figure 15. Test circuit for inductive load switching and diode recovery times







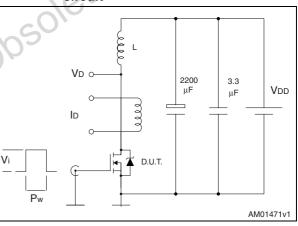
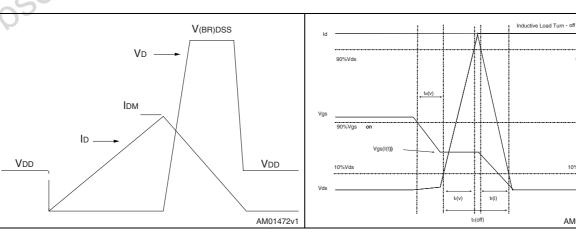


Figure 18. Switching time waveform



90%ld

10%lc

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4 Package mechanical data

In order to meet environmental requirements, ST offers these devices in different grades of ECOPACK[®] packages, depending on their level of environmental compliance. ECOPACK[®] specifications, grade definitions and product status are available at: www.st.com. ECOPACK is an ST trademark.

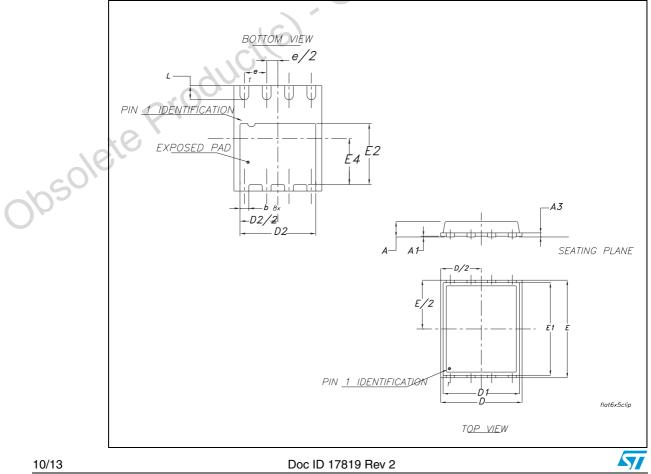
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obsolete Product(s). Obsolete Product(s)

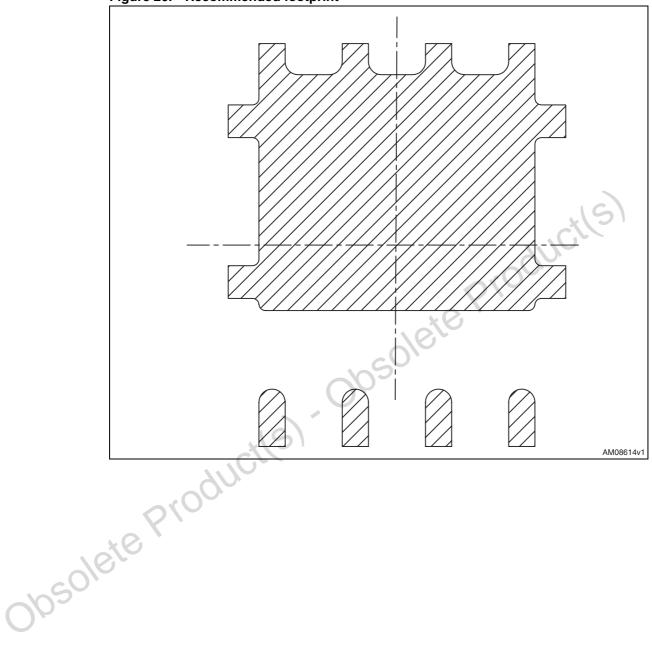
Dim	mm					
Dim. —	Min.	Тур.	Max.			
A	0.80	0.83	0.93			
A1		0.02	0.05			
A3		0.20				
b	0.35	0.40	0.47			
D		5.00				
D1		4.75				
D2	4.15	4.20	4.25			
E		6.00	1110			
E1		5.75	000			
E2	3.43	3.48	3.53			
E4	2.58	2.63	2.68			
е		1.27				
L	0.70	0.80	0.90			

Table 8. PowerFLAT[™] (5x6) mechanical data











5 Revision history

Table 9.Document revision history

	Date	Revision	Changes
	02-Aug-2010	1	First release.
	26-Apr-2011	2	Updated R _{DS(on)} value, and figures 2, 5, 7, 10, 11 and 12. Updated Section 4.
obsole	tepro	Jucil	obsolete Production



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